



PERRY JOHNSON LABORATORY ACCREDITATION, INC.

Certificate of Accreditation

Perry Johnson Laboratory Accreditation, Inc. has assessed the Laboratory of:

Custom Calibrations Solutions
535 US HWY 130, Hamilton, NJ, 08691

(Hereinafter called the Organization) and hereby declares that Organization is accredited in accordance with the recognized International Standard:

ISO/IEC 17025:2017
And meets the requirements of ANSI/NCSL Z540-1-1994

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (as outlined by the joint ISO-ILAC-IAF Communiqué dated April 2017):

Photometry and Radiometry
(As detailed in the supplement)

Accreditation claims for such testing and/or calibration services shall only be made from addresses referenced within this certificate. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

Tracy Szerszen
President

Perry Johnson Laboratory
Accreditation, Inc. (PJLA)
755 W. Big Beaver, Suite 1325
Troy, Michigan 48084

Initial Accreditation Date:

September 27, 2022

Issue Date:

September 27, 2022

Expiration Date:

January 26, 2024

Accreditation No.:

61599

Certificate No.:

L22-638

The validity of this certificate is maintained through ongoing assessments based on a continuous accreditation cycle. The validity of this certificate should be confirmed through the PJLA website: www.pilabs.com



Certificate of Accreditation: Supplement

Custom Calibrations Solutions

535 US HWY 130, Hamilton, NJ, 08691
Contact Name: Mr.Randy Yousey Phone: 609-530-9000

Accreditation is granted to the facility to perform the following calibrations:

Optical

MEASURED INSTRUMENT, QUANTITY OR GAUGE	RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE	CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (\pm)	CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED
Optical Wavelength x ^F	1 530 nm	0.16 μ m	Reference Wavelength Standards monitored with Wavelength meter

1. The CMC (Calibration and Measurement Capability) stated for calibrations included on this scope of accreditation represents the smallest measurement uncertainty attainable by the laboratory when performing a more or less routine calibration of a nearly ideal device under nearly ideal conditions. It is typically expressed at a confidence level of 95 % using a coverage factor k (usually equal to 2). The actual measurement uncertainty associated with a specific calibration performed by the laboratory will typically be larger than the CMC for the same calibration since capability and performance of the device being calibrated and the conditions related to the calibration may reasonably be expected to deviate from ideal to some degree.
2. The presence of a superscript F means that the laboratory performs calibration of the indicated parameter at its fixed location. Example: Outside Micrometer^F would mean that the laboratory performs this calibration at its fixed location.
3. The above scope of accreditation was created based on a former ILAC MRA Signatory's certificate policy. Based on the intent of the ILAC MRA, PJLA recognizes other scopes issued by other ILAC signatories. This scope will be modified based on PJLA's Policy following the next on-site assessment.